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OS DESIGN DEPT.

MGXW6 Series EMI/EMS Test results

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No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.1	(1)Meets the undermentioned standard. FCC Part15 classA , VCCI classA CISPR32 classA , EN55032-A	ok
2	Radiated emission	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Testing circuitry Fig.1	(1)Meets the under mentioned standard. FCC Part15 classA , VCCI classA CISPR32 classA , EN55032-A	ok
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Contact discharge voltage 4[kV] (EN61000-4-2 Level 2) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	ok
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4)Testing field strength (Level 3) ① 10 [V/m] (80MHz to 1.0GHz) ② 3 [V/m] (1.4GHz to 2.0GHz) ③ 1 [V/m] (2.0GHz to 2.7GHz) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	ok
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure.	ok
6	Surge immunity test (EN61000-4-5)	(1) Rated input (2) Rated load (3) Ambient temp. $25 \pm 10^{\circ}\text{C}$ (4) Test voltage Line to line 2[kV] (Level 3) (5) Testing circuitry Fig.2	(1)The power supply is not stop. (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	ok

Conditions

Test : Line conduction , Radiated emission
 Static electricity immunity test
 Radiated, radio-frequency, electromagnetic field immunity test
 Electrical fast transient / burst immunity test

Model Name : MGXW6□□

○Testing circuitry

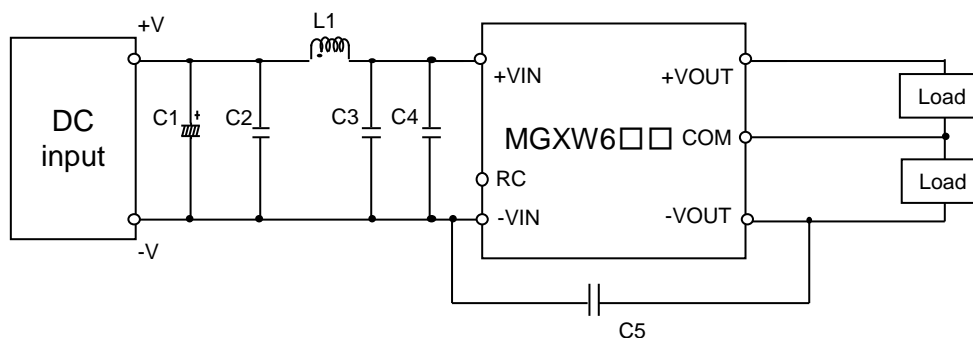


Fig.1 Testing circuitry

- C1 : MGXW624□□ 100V 39 μ F Electric capacitor (LXVseries NIPPON CHEMI-CON)
- C2 : MGXW624□□ 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C3 : MGXW624□□ 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C4 : MGXW624□□ 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
- C5 : MGXW624□□ 2kV 2200pF Ceramic capacitor (GR443QR73D222K MURATA MANUFACTURING)
- L1 : MGXW624□□ 1050mA 22 μ H Inductor(LQH5BPN220MT0 MURATA MANUFACTURING)

Conditions

Test : Surge immunity test

Model Name : MGXW6□□

○Testing circuitry

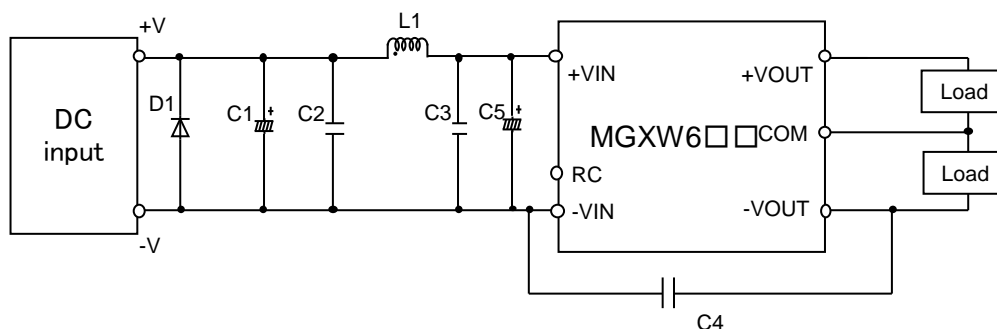


Fig.2 Testing circuitry

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|------|-----------|--|
| C1 : | MGXW624□□ | 100V 180 μ F Electric capacitor (LXVseries NIPPON CHEMI-CON) |
| C2 : | MGXW624□□ | 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING) |
| C3 : | MGXW624□□ | 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING) |
| C4 : | MGXW624□□ | 2kV 2200pF Ceramic capacitor (GR443QR73D222K MURATA MANUFACTURING) |
| C5 : | MGXW624□□ | 100V 180 μ F Electric capacitor (LXVseries NIPPON CHEMI-CON) |
| L1 : | MGXW624□□ | 1050mA 22 μ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING) |
| D1 : | MGXW624□□ | 400V 3A Diode (S3L40U SHINDENGEN) |